## INTERNATIONAL STANDARD

# IEC 60747-16-1

2001

AMENDMENT 1 2007-01

Amendment 1

Semiconductor devices –

Part 16-1: Microwave integrated circuits – Amplifiers https://standards.iteh.ai) Document Preview

IEC 60747-16-1:2001/AMD1:2007

https://standards.iteh.ai/catalog/standards/iec/daf27f61-ab38-47e8-8da8-de806d39fd37/iec-60747-16-1-2001-amd1-2007

© IEC 2007 Droits de reproduction réservés — Copyright - all rights reserved

International Electrotechnical Commission, 3, rue de Varembé, PO Box 131, CH-1211 Geneva 20, Switzerland Telephone: +41 22 919 02 11 Telefax: +41 22 919 03 00 E-mail: inmail@iec.ch Web: www.iec.ch



Commission Electrotechnique Internationale International Electrotechnical Commission Международная Электротехническая Комиссия



For price, see current catalogue

Q

#### FOREWORD

This amendment has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this amendment is based on the following documents:

FDIS	Report on voting
47E/305/FDIS	47E/317/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

Page 2

CONTENTS

Replace the titles of Subclauses 5.11, 5.13, 5.14, 5.15, 5.19, and 5.21 by the following new

(https://standards.iteh.ai)

*titles:*  $\underline{HC.60/4/-16-1.2001/AWD1.2007}$ ndards.iteh.ai/catalog/standards/iec/daf27f61-ab38-47e8-8da8-de806d39fd37/iec-60747-16-1-2001-amd1-2007 5.11 Intermodulation distortion (two-tone) ( $P_1/P_p$ )

- 5.13 Magnitude of the input reflection coefficient (input return loss) ( $|S_{11}|$ )
- 5.14 Magnitude of the output reflection coefficient (output return loss) ( $|S_{22}|$ )
- 5.15 Magnitude of the reverse transmission coefficient (isolation) ( $|S_{12}|$ )
- 5.19 *n*th order harmonic distortion ratio  $(P_1/P_{nth})$
- 5.21 Spurious intensity under specified load VSWR ( $P_0/P_{sp}$ )

Add the titles of following new clause and subclauses:

- 5.22 Adjacent channel power ratio  $(P_{o(mod)}/P_{adj})$
- 6 Verifying methods
- 6.1 Load mismatch tolerance ( $\Psi_L$ )
- 6.2 Source mismatch tolerance ( $\Psi_{\rm S}$ )
- 6.3 Load mismatch ruggedness ( $\Psi_R$ )

Add the titles of following new figures:

Figure 12 – Circuit for the measurement of the adjacent channel power ratio Figure 13 – Circuit for the verification of load mismatch tolerance in method 1 Figure 14 – Circuit for the verification of load mismatch tolerance in method 2 Figure 15 – Circuit for the verification of source mismatch tolerance in method 1 Figure 16 – Circuit for the verification of source mismatch tolerance in the method 2 Figure 17 – Circuit for the verification of load mismatch ruggedness

#### Page 5

#### 2 Normative references

Replace existing references IEC 60617-12, IEC 60617-13 and IEC 60747-1 as follows:

IEC 60617:2001, Graphical symbols for diagrams

IEC 60747-1:2006, Semiconductor devices – Part 1: General

IEC 60747-4:-, Semiconductor devices – Discrete devices – Part 4: Microwave diodes and transistors<sup>1</sup>

IEC 60747-16-2:2001, Semiconductor devices – Part 16-2: Microwave integrated circuits – Frequency prescalers

IEC 60747-16-4:2004, Semiconductor devices – Part 16-4: Microwave integrated circuits – Switches

IEC/TS 61340-5-1:1998, Electrostatics - Part 5-1: Protection of electronic devices from electrostatic phenomena - General requirements

IEC/TS 61340-5-2:1999, Electrostatics - Part 5-2: Protection of electronic devices from electrostatic phenomena - User guide

#### 3 Terminology

Replace, on pages 6 and 7, the terms 3.7, 3.9, 3.10, 3.11, 3.14, and 3.16 by the following new terms:

#### 3.7

#### intermodulation distortion $P_1/P_n$

ratio of the fundamental component of the output power to the *n*th order component of the output power, at a specified input power

#### 3.9

magnitude of the input reflection coefficient (input return loss)  $|S_{11}|$  see 3.5.2.1 of IEC 60747-7

#### 3.10

magnitude of the output reflection coefficient (output return loss)  $|S_{22}|$  see 3.5.2.2 of IEC 60747-7

3.11 magnitude of the reverse transmission coefficient (isolation)  $|S_{12}|$ see 3.5.2.4 of IEC 60747-7

#### 3.14

#### *n*th order harmonic distortion ratio $P_1/P_{nth}$

ratio of the power of the fundamental frequency measured at the output port of the device to the power of the *n*th order harmonic component measured at the output port for a specified output power

<sup>&</sup>lt;sup>1</sup> The second edition of IEC 60747-4, which is cited in this standard, and to which terms introduced in this amendment refer, is currently in preparation (ADIS).

3.16

## spurious intensity under specified load VSWR $P_{o}/P_{sp}$

ratio of the power of the fundamental frequency measured at the output port of the device to the maximum spurious power measured at the output port under specified load VSWR

Add the following new terms:

#### 3.17 output power Po see 3.3 of IEC 60747-16-2 3.18 output power at 1 dB gain compression Po(1dB) see 8.2.13 of IEC 60747-4 3.19 noise figure F see 702-08-57 of IEC 60050-702 3.20 power added efficiency $\eta_{add}$ see 8.2.15 of IEC 60747-4 3.21 adjacent channel power ratios://standards.iteh.ai) Po(mod) /Padj see 3.10 of IEC 60747-16-4 3.22 load mismatch tolerance $\Psi_{L}$

ps://stand.see 7.2.20 of IEC 60747-4 /jec/da/27/61-ab38-47e8-8da8-de806d39fd37/jec-60747-16-1-2001-amd1-2007

#### 3.23

source mismatch tolerance  $\Psi_{S}$ see 7.2.21 of IEC 60747-4

### 3.24 load mismatch ruggedness $\Psi_R$ see 7.2.22 of IEC 60747-4

Page 9

#### 4.3.1 Detailed block diagram – Functional blocks

Replace, in the last paragraph, "IEC 60617-12 or IEC 60617-13" by "IEC 60617".

Page 12

#### 4.6.2 Dynamic or a.c. characteristics

Replace the title and parameters 4.6.2.10, 4.6.2.20 and 4.6.22 by the following new title and new parameters:

Parameters		Min.	Max.	Types				
				Α	В	С	D	
4.6.2.10	Intermodulation distortion	+				+	+	
4.6.2.20	<i>n</i> th order harmonic distortion ratio (where appropriate) (note 2)	+					+	
4.6.2.22	Spurious intensity under specified load VSWR (where appropriate) (note 2)	+					+	

#### 4.6.2 Dynamic or r.f. characteristics

#### Add the following new parameters:

Parameters		Min.	Max.	Types				
				A	в	с	D	
4.6.2.23	Adjacent channel power ratio (where appropriate)	+					+	
4.6.2.24	Load mismatch tolerance (where appropriate)		+				+	
4.6.2.25	Source mismatch tolerance (where appropriate)		+				+	
4.6.2.26	Load mismatch ruggedness (where appropriate)	ds	+				+	

Page 14

# https://standards.iteh.ai

#### 4.7 Mechanical and environmental ratings, characteristics and data

Replace "IEC 60747-1, Chapter VI, clause 7" by "Subclause 5.10 and 5.11 of IEC 60747-1:2006".

#### 4.8.8 Handling precautions

Replace "IEC 60747-1, Chapter IX" by "IEC 61340-5-1 and IEC 61340-5-2".

Page 15

#### 5.1.2 General precautions

Replace "clause 2 of IEC 60747-1, Chapter VII, Section One" by "clause 6.3, 6.4 and 6.6 of IEC 60747-1:2006".

#### 5.1.3 Handling precautions

Replace "clause 1 of IEC 60747-1, Chapter IX" by "IEC 61340-5-1 and IEC 61340-5-2".

Page 25

Replace the existing title of Subclause 5.11 by the following new title:

#### 5.11 Intermodulation distortion (two-tone) $(P_1/P_n)$

#### 5.11.3 Principle of measurement

Replace, in the first line " $P_n$  and  $P_1$ " by " $P_1$  and  $P_n$ ".

Replace Equation (14) by the following:

$$P_1 = P_b + L_2$$
 (14)

Replace the text after Equations (13), (14), (15) and (16) as follows:

where

- $P_1$  and  $P_n$  are the powers of the fundamental signal and the intermodulation distortion, respectively;
- $P_{a}$ ,  $P_{b}$  and  $P_{c}$  are the values indicated by the spectrum analyser corresponding to  $P_{i}$ ,  $P_{1}$  and  $P_{n}$ , respectively:
- $L_1$  is the difference between the loss  $L_A$  and  $L_B$  where  $L_A$  is the loss from point E to point A and  $L_B$  is the loss from point E to point B shown in Figure 3, respectively.  $L_2$  is the circuit loss from point C to point D shown in Figure 3.  $P_i$ ,  $P_1$ ,  $P_n$ ,  $P_a$ ,  $P_b$  and  $P_c$  are expressed in dBm.  $L_1$  and  $L_2$  are expressed in decibels.

The intermodulation distortion,  $P_1/P_n$ , which is expressed in dBc, is derived from Equations (14) and (15) as follows: IEC 60747-16-12001/AMD12007

Page 28

Replace the existing title of subclause 5.13 by the following new title:

#### 5.13 Magnitude of the input reflection coefficient (input return loss) ( $|S_{11}|$ )

Replace, in Equation (17), the symbol " $|s_{11}|$ " by " $|S_{11}|$ ".

Page 29

#### Replace, the symbol " $(|s_{22}|)$ " by " $(|S_{22}|)$ " in the following places:

in both the title and text of subclause 5.14, on page 30 in Equation (18); on page 31, in Subclause 5.14.2.1 and in Equation (19),

Page 32

#### 5.14.2.4 Circuit description and requirements

Delete, in the second paragraph of this subclause, the symbol " $|s_{22}|$ ".